

Test Laboratory: Compliance Certification Services

HAC_H_Device Cell band (Backlight on)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA Cellular band; Frequency: 824.7 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 0.119 A/m

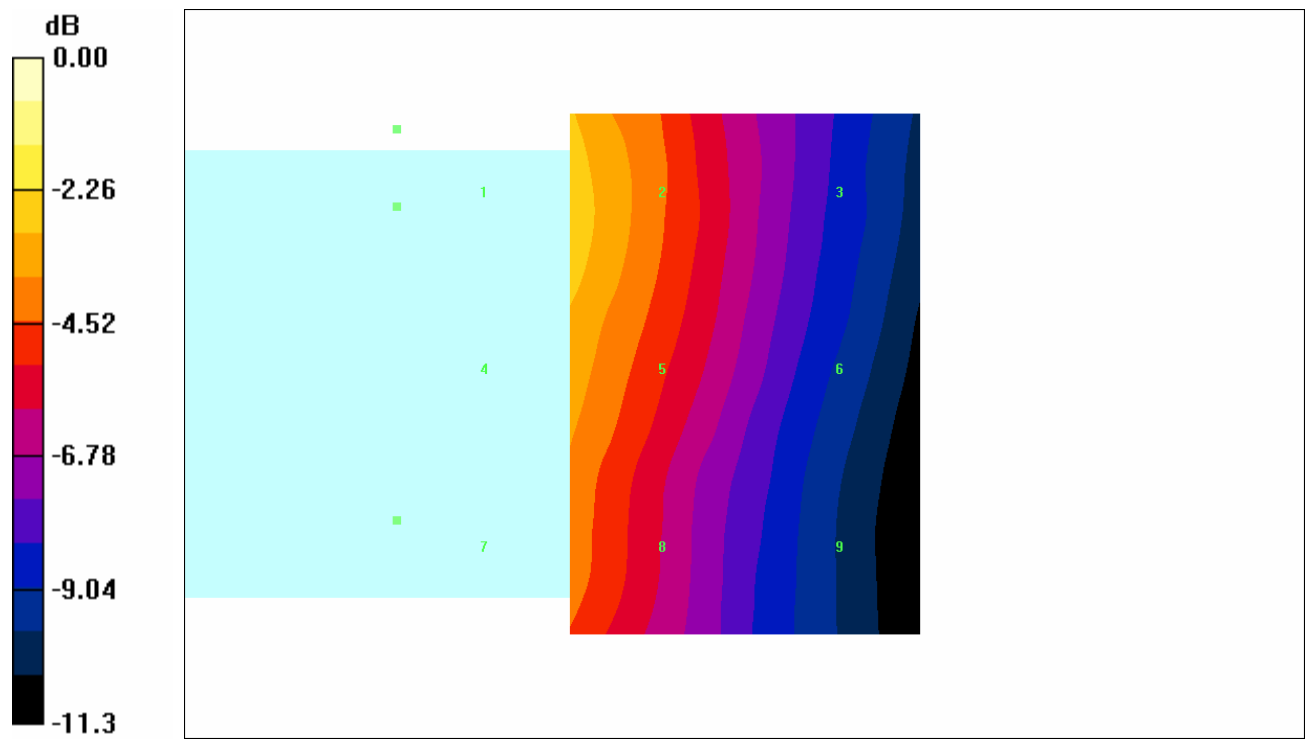
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.160	Grid 2 0.119	Grid 3 0.076
Grid 4 0.155	Grid 5 0.116	Grid 6 0.074
Grid 7 0.142	Grid 8 0.103	Grid 9 0.066

Grid 1 0.160	Grid 2 0.119	Grid 3 0.076
Grid 4 0.155	Grid 5 0.116	Grid 6 0.074
Grid 7 0.142	Grid 8 0.103	Grid 9 0.066

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.160A/m

Test Laboratory: Compliance Certification Services

HAC_H_Device Cell band (Backlight on)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA Cellular band; Frequency: 836.49 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

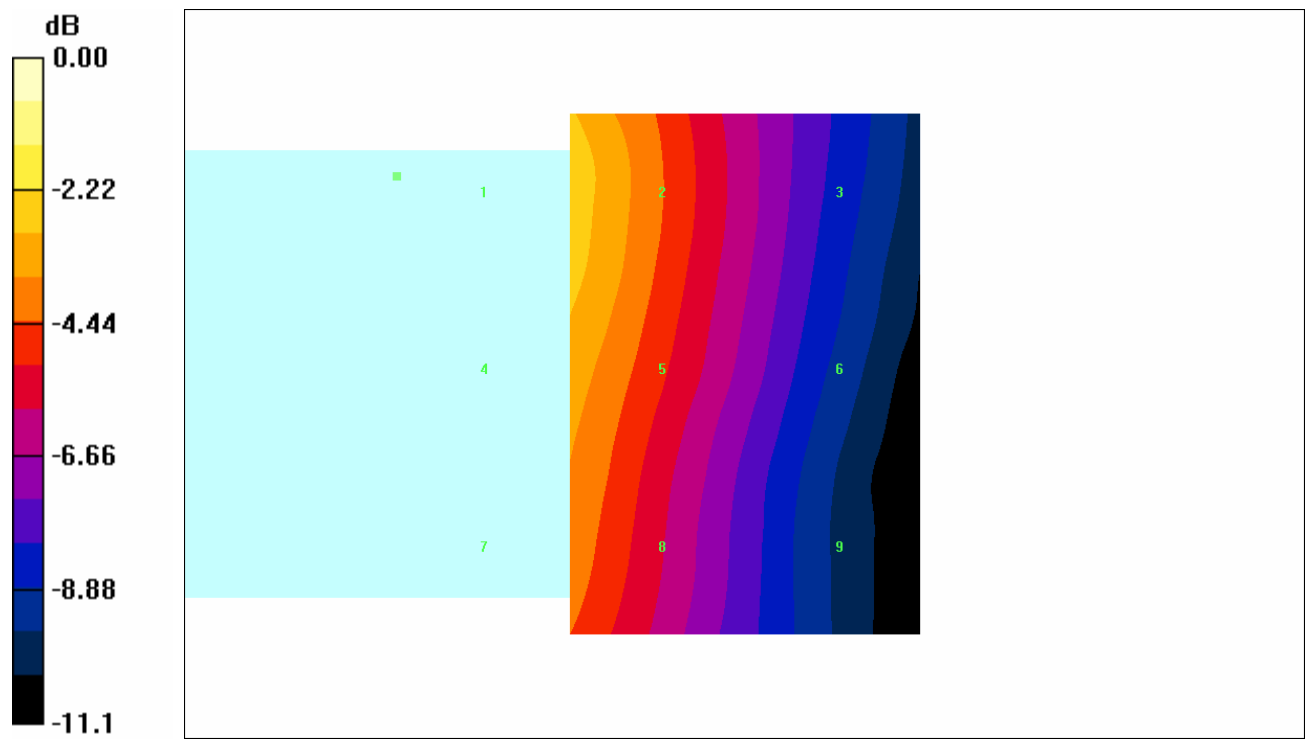
Maximum value of Total field (slot averaged) = 0.114 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.152	Grid 2 0.114	Grid 3 0.073	Grid 1 0.152	Grid 2 0.114	Grid 3 0.073
Grid 4 0.145	Grid 5 0.111	Grid 6 0.071	Grid 4 0.145	Grid 5 0.111	Grid 6 0.071
Grid 7 0.137	Grid 8 0.099	Grid 9 0.064	Grid 7 0.137	Grid 8 0.099	Grid 9 0.064

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.152A/m

Test Laboratory: Compliance Certification Services

HAC_H_Device Cell band (Backlight on)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA Cellular band; Frequency: 848.31 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

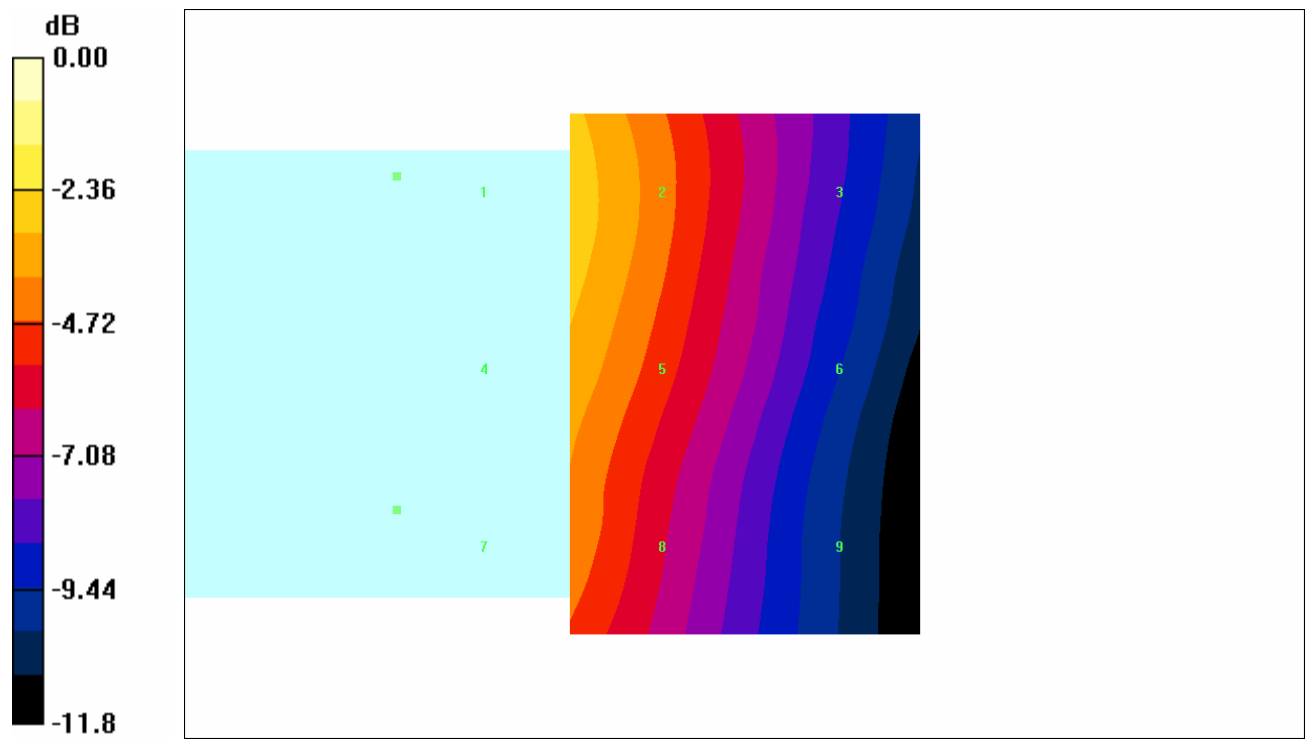
Maximum value of Total field (slot averaged) = 0.113 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.152	Grid 2 0.113	Grid 3 0.073	Grid 1 0.152	Grid 2 0.113	Grid 3 0.073
Grid 4 0.144	Grid 5 0.109	Grid 6 0.070	Grid 4 0.144	Grid 5 0.109	Grid 6 0.070
Grid 7 0.135	Grid 8 0.097	Grid 9 0.062	Grid 7 0.135	Grid 8 0.097	Grid 9 0.062

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.152A/m

Test Laboratory: Compliance Certification Services

HAC_H_Device Cell band (Backlight off)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA Cellular band; Frequency: 824.7 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

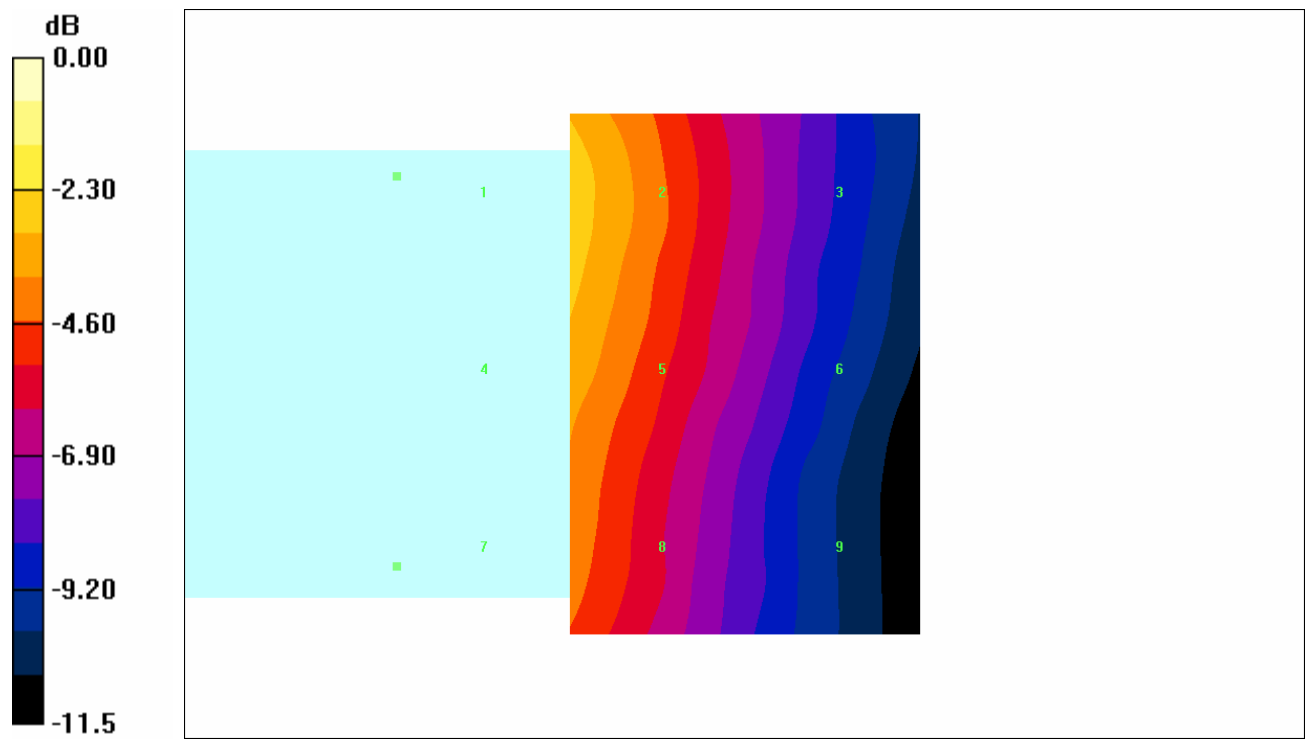
Maximum value of Total field (slot averaged) = 0.120 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.162	Grid 2 0.120	Grid 3 0.077	Grid 1 0.162	Grid 2 0.120	Grid 3 0.077
Grid 4 0.154	Grid 5 0.117	Grid 6 0.074	Grid 4 0.154	Grid 5 0.117	Grid 6 0.074
Grid 7 0.145	Grid 8 0.104	Grid 9 0.066	Grid 7 0.145	Grid 8 0.104	Grid 9 0.066

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



Test Laboratory: Compliance Certification Services

HAC_H_Device Cell band (Backlight off)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA Cellular band; Frequency: 836.49 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

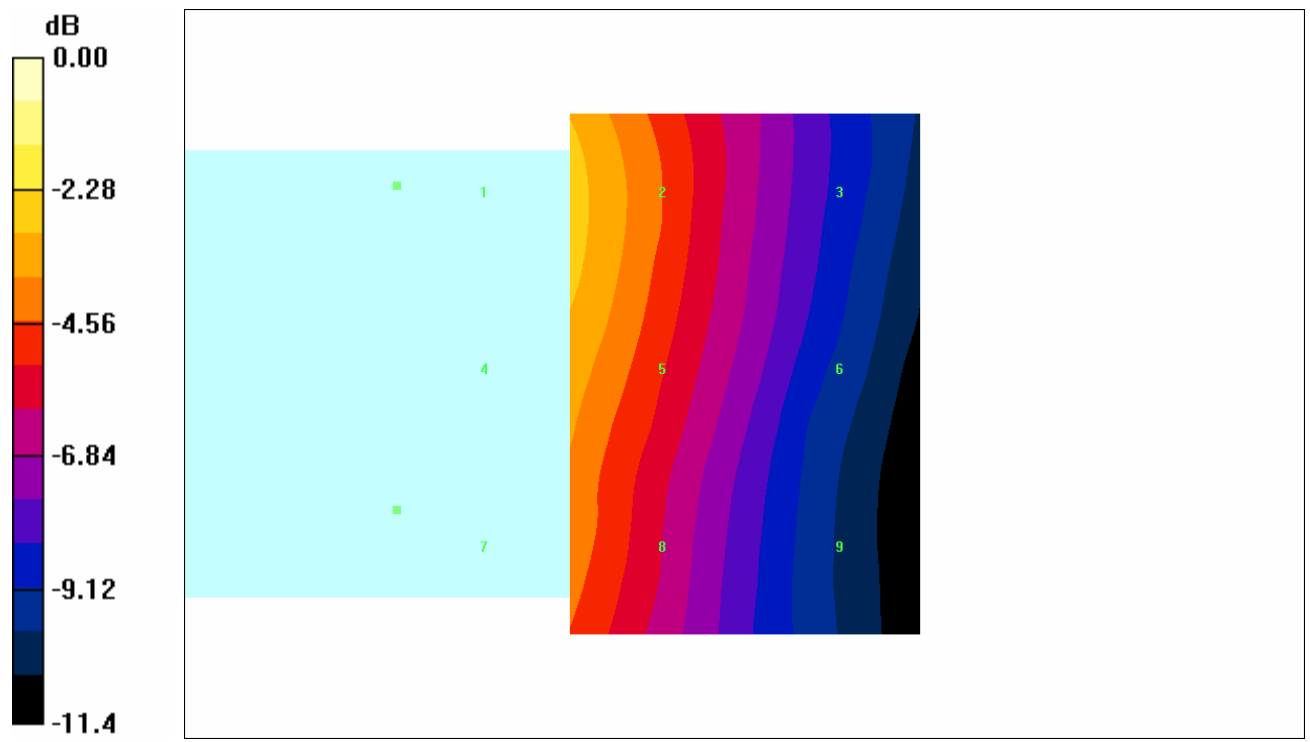
Maximum value of Total field (slot averaged) = 0.113 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.154	Grid 2 0.113	Grid 3 0.073	Grid 1 0.154	Grid 2 0.113	Grid 3 0.073
Grid 4 0.146	Grid 5 0.111	Grid 6 0.070	Grid 4 0.146	Grid 5 0.111	Grid 6 0.070
Grid 7 0.136	Grid 8 0.099	Grid 9 0.063	Grid 7 0.136	Grid 8 0.099	Grid 9 0.063

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.154A/m

Test Laboratory: Compliance Certification Services

HAC_H_Device Cell band (Backlight off)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA Cellular band; Frequency: 848.31 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

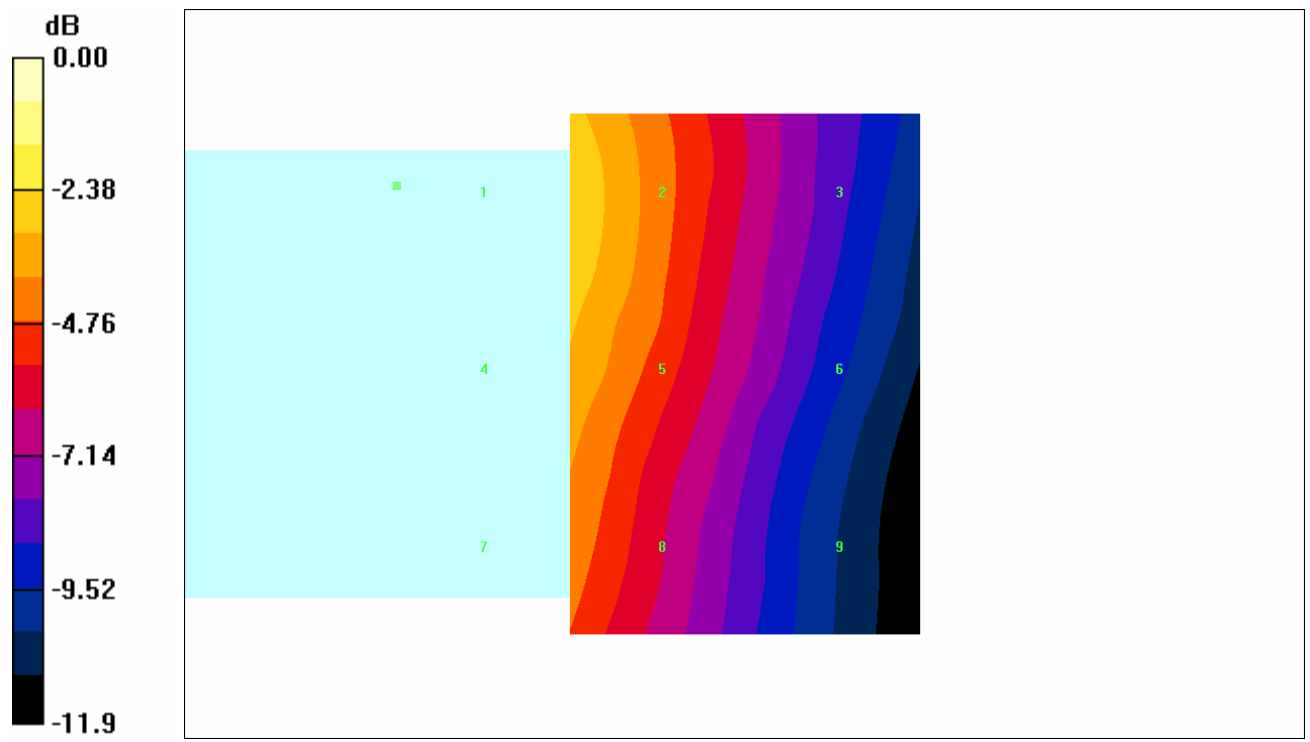
Maximum value of Total field (slot averaged) = 0.116 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.154	Grid 2 0.116	Grid 3 0.074	Grid 1 0.154	Grid 2 0.116	Grid 3 0.074
Grid 4 0.147	Grid 5 0.112	Grid 6 0.071	Grid 4 0.147	Grid 5 0.112	Grid 6 0.071
Grid 7 0.136	Grid 8 0.098	Grid 9 0.062	Grid 7 0.136	Grid 8 0.098	Grid 9 0.062

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



Test Laboratory: Compliance Certification Services

1_HAC_H-Device PCS band (Backlight on)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA PCS band; Frequency: 1851.25 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

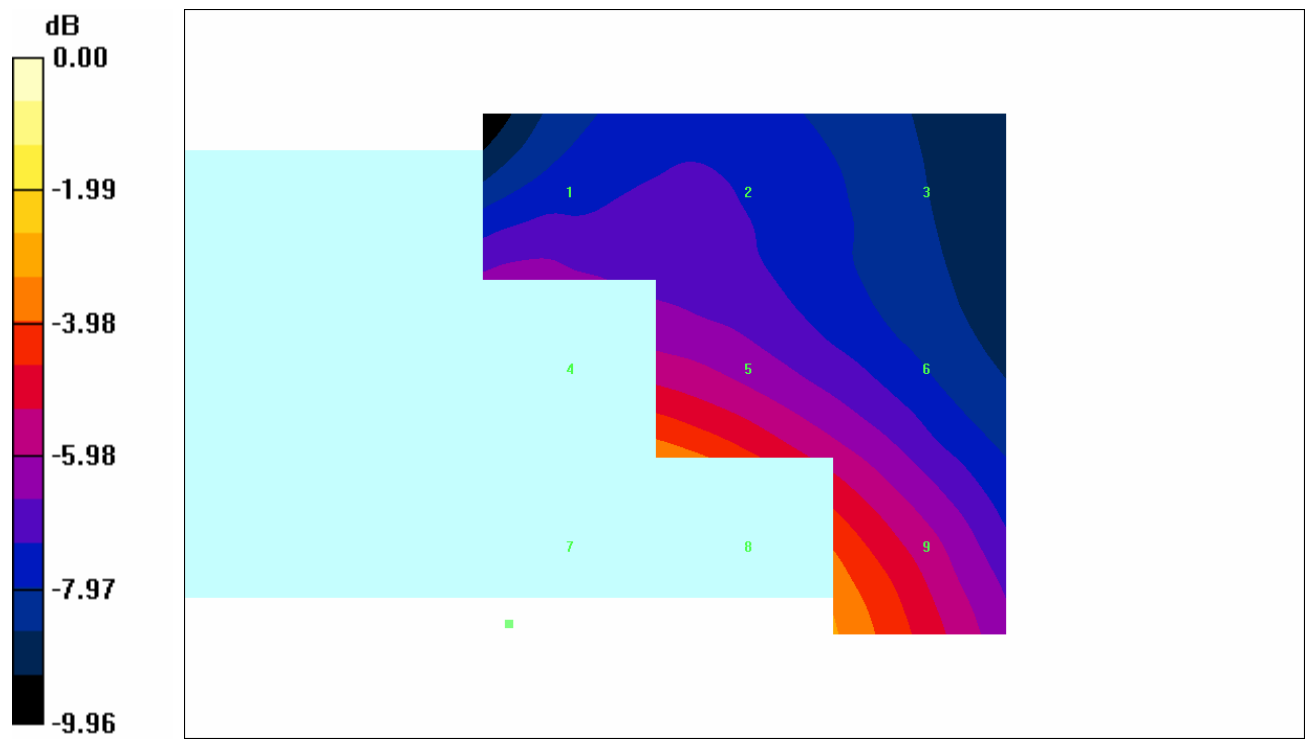
Maximum value of Total field (slot averaged) = 0.077 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.054	Grid 2 0.051	Grid 3 0.046	Grid 1 0.054	Grid 2 0.051	Grid 3 0.046
Grid 4 0.081	Grid 5 0.075	Grid 6 0.058	Grid 4 0.081	Grid 5 0.075	Grid 6 0.058
Grid 7 0.111	Grid 8 0.104	Grid 9 0.077	Grid 7 0.111	Grid 8 0.104	Grid 9 0.077

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



Test Laboratory: Compliance Certification Services

1_HAC_H-Device PCS band (Backlight on)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA PCS band; Frequency: 1880 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

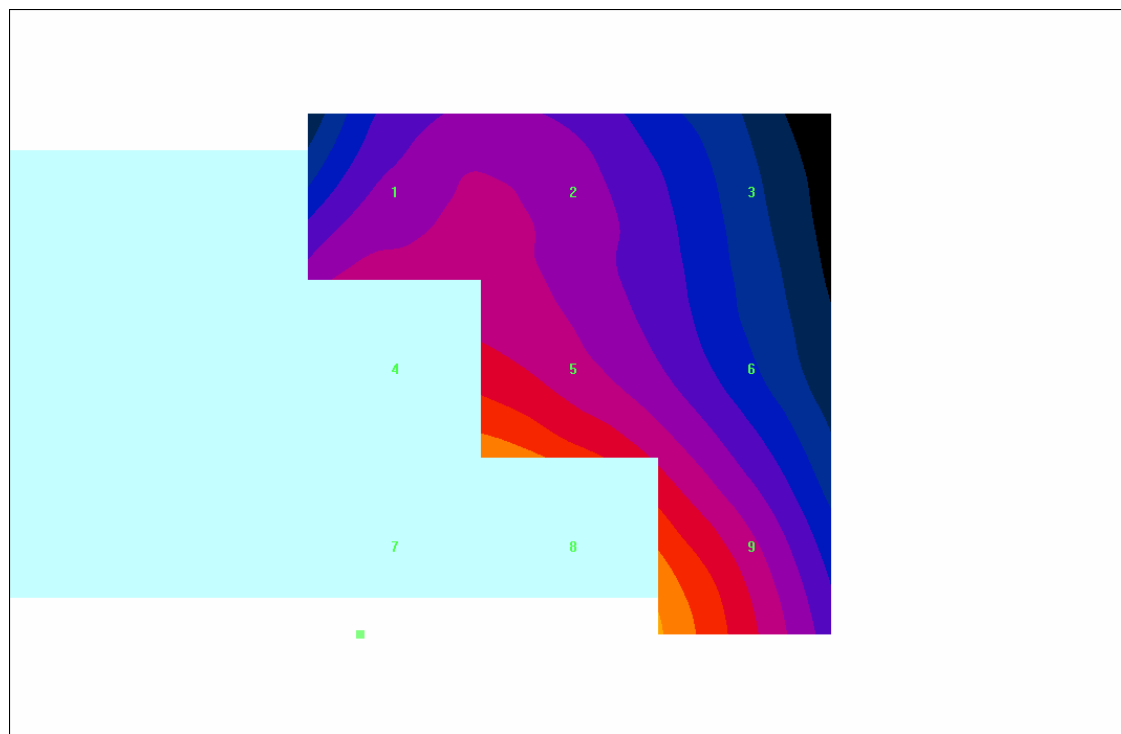
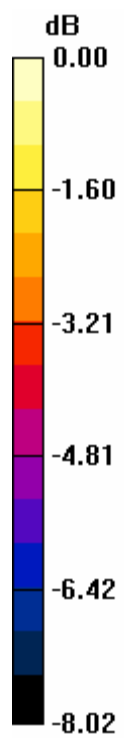
Maximum value of Total field (slot averaged) = 0.083 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.066	Grid 2 0.066	Grid 3 0.059	Grid 1 0.066	Grid 2 0.066	Grid 3 0.059
Grid 4 0.086	Grid 5 0.082	Grid 6 0.068	Grid 4 0.086	Grid 5 0.082	Grid 6 0.068
Grid 7 0.112	Grid 8 0.107	Grid 9 0.083	Grid 7 0.112	Grid 8 0.107	Grid 9 0.083

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.112A/m

Test Laboratory: Compliance Certification Services

1_HAC_H-Device PCS band (Backlight on)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA PCS band; Frequency: 1908.75 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

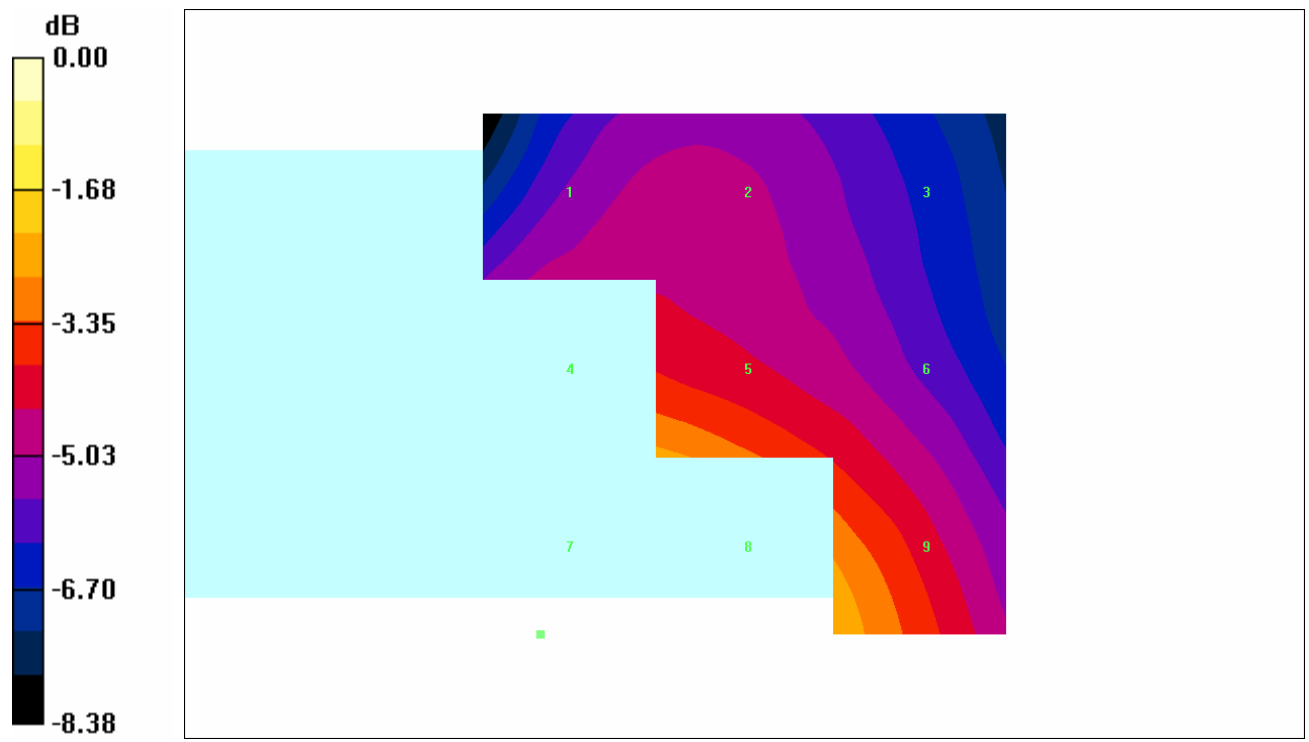
Maximum value of Total field (slot averaged) = 0.082 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.064	Grid 2 0.064	Grid 3 0.059	Grid 1 0.064	Grid 2 0.064	Grid 3 0.059
Grid 4 0.082	Grid 5 0.080	Grid 6 0.068	Grid 4 0.082	Grid 5 0.080	Grid 6 0.068
Grid 7 0.107	Grid 8 0.102	Grid 9 0.082	Grid 7 0.107	Grid 8 0.102	Grid 9 0.082

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.107A/m

Test Laboratory: Compliance Certification Services

2_HAC_H-Device PCS band (Backlight off)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA PCS band; Frequency: 1851.25 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 0.077 A/m

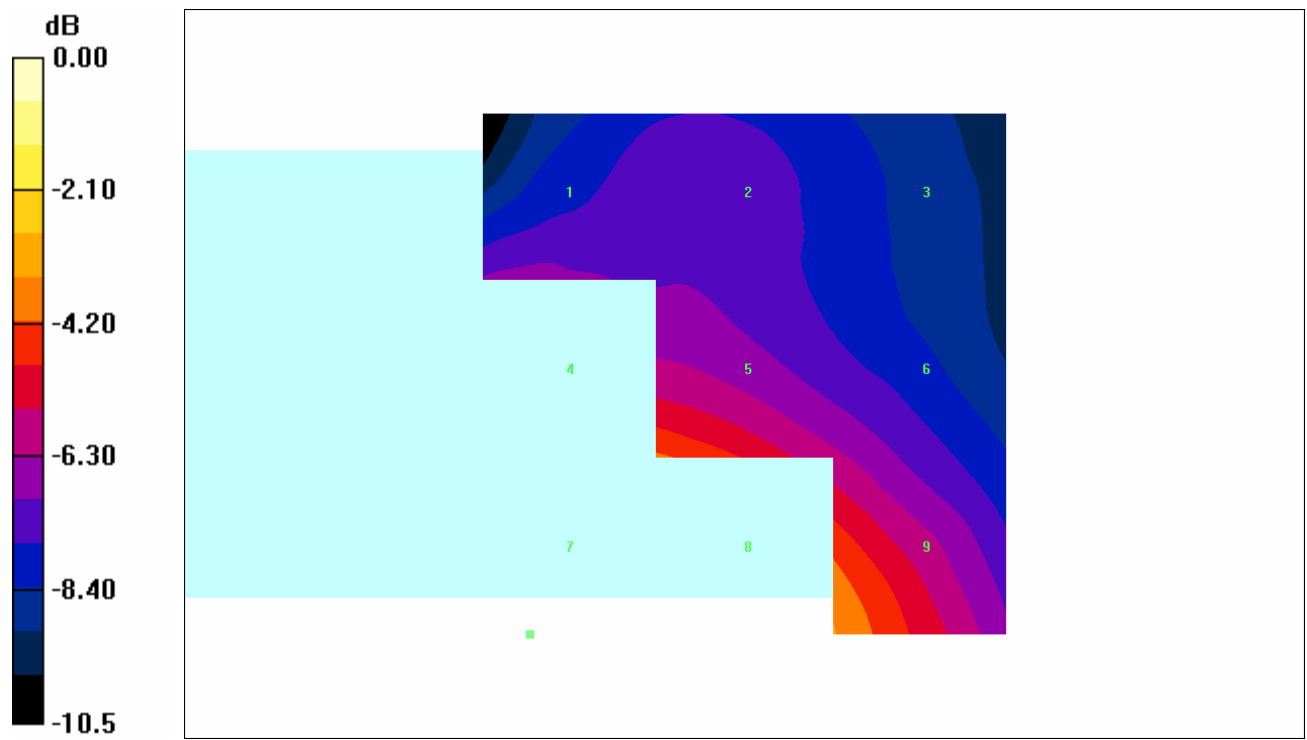
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3
0.053	0.051	0.046
Grid 4	Grid 5	Grid 6
0.078	0.072	0.057
Grid 7	Grid 8	Grid 9
0.115	0.107	0.077

Grid 1	Grid 2	Grid 3
0.053	0.051	0.046
Grid 4	Grid 5	Grid 6
0.078	0.072	0.057
Grid 7	Grid 8	Grid 9
0.115	0.107	0.077

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.115A/m

Test Laboratory: Compliance Certification Services

2_HAC_H-Device PCS band (Backlight off)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA PCS band; Frequency: 1880 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

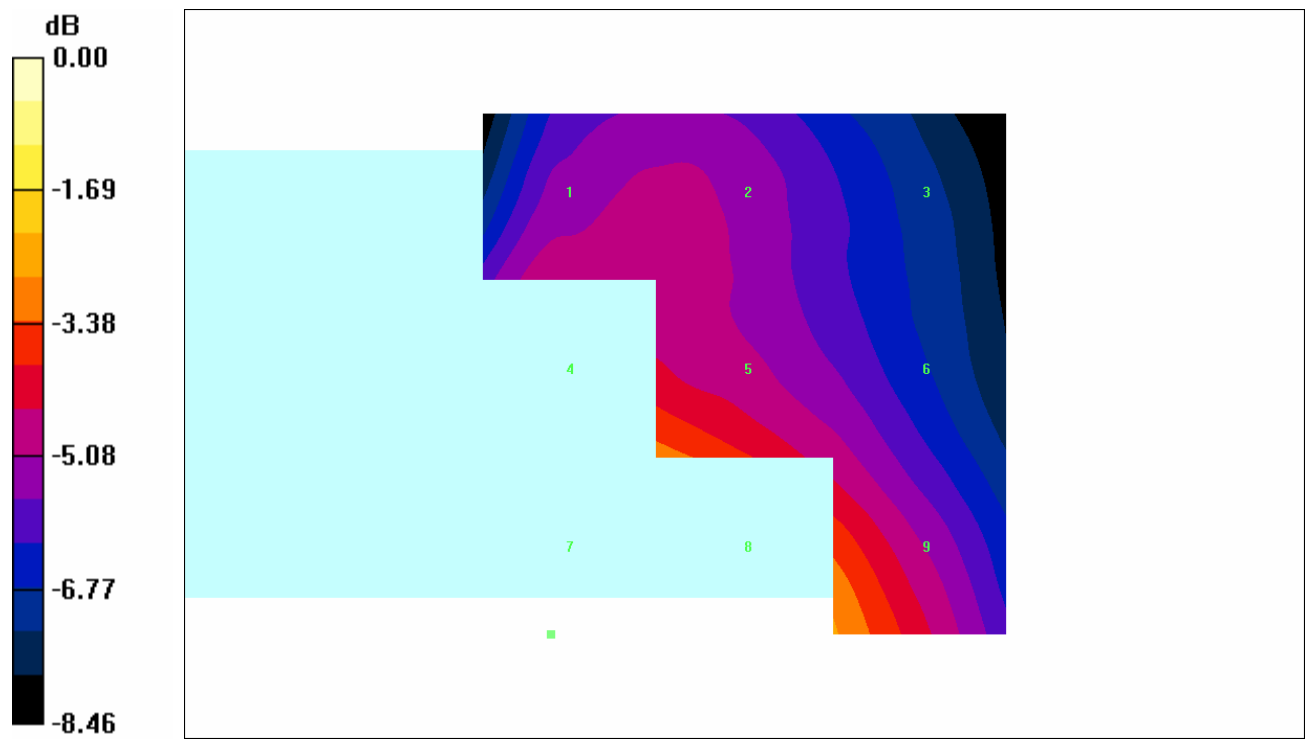
Maximum value of Total field (slot averaged) = 0.087 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.069	Grid 2 0.069	Grid 3 0.060	Grid 1 0.069	Grid 2 0.069	Grid 3 0.060
Grid 4 0.088	Grid 5 0.084	Grid 6 0.069	Grid 4 0.088	Grid 5 0.084	Grid 6 0.069
Grid 7 0.119	Grid 8 0.114	Grid 9 0.087	Grid 7 0.119	Grid 8 0.114	Grid 9 0.087

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.119A/m

Test Laboratory: Compliance Certification Services

2_HAC_H-Device PCS band (Backlight off)

DUT: Kyocera; Type: KX1; Serial: 20-M4004-01B

Communication System: CDMA PCS band; Frequency: 1908.75 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1$ kg/m³

Phantom section: H Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 - SN6157; ; Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

H Scan - H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

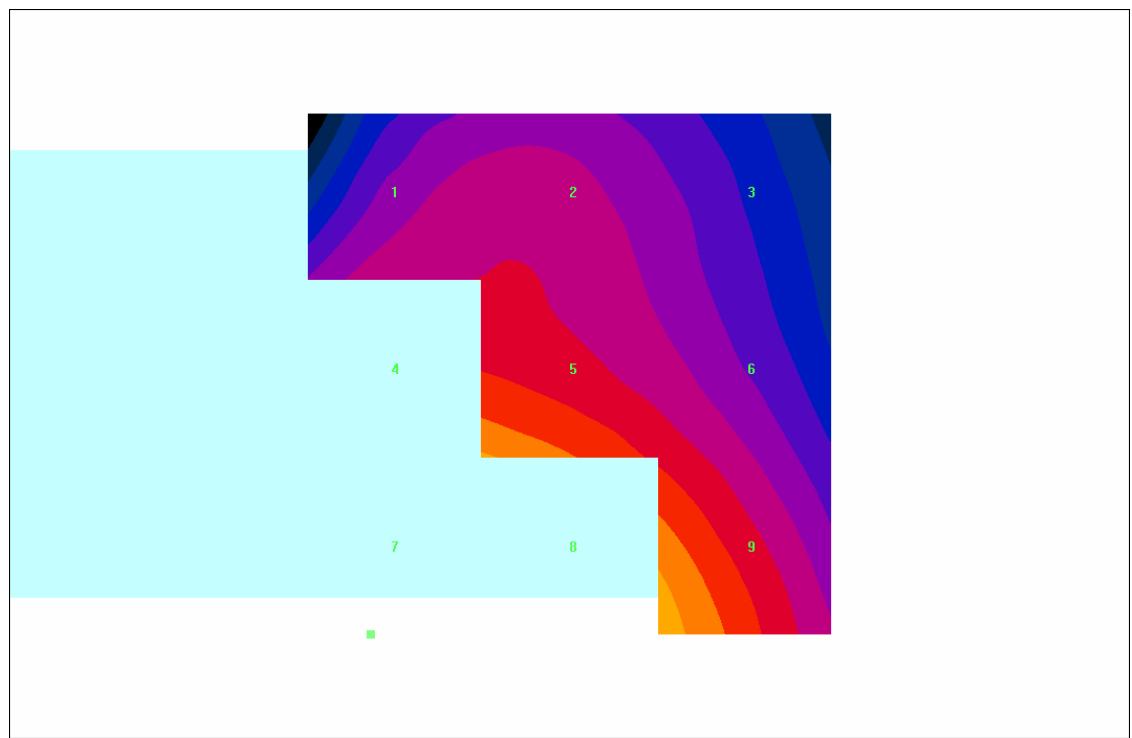
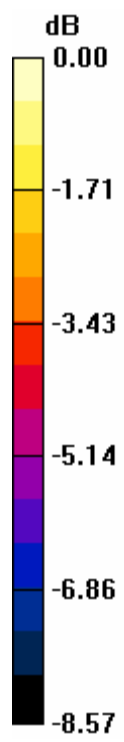
Maximum value of Total field (slot averaged) = 0.084 A/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1 0.066	Grid 2 0.066	Grid 3 0.061	Grid 1 0.066	Grid 2 0.066	Grid 3 0.061
Grid 4 0.084	Grid 5 0.081	Grid 6 0.069	Grid 4 0.084	Grid 5 0.081	Grid 6 0.069
Grid 7 0.111	Grid 8 0.107	Grid 9 0.084	Grid 7 0.111	Grid 8 0.107	Grid 9 0.084

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 0.111A/m